

MOS FIELD EFFECT TRANSISTOR 2SK2411, 2SK2411-Z

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

The 2SK2411 is N-Channel MOS Field Effect Transistor designed for high speed switching applications.

FEATURES

Low On-Resistance

 $\begin{array}{l} R_{DS(on)1} = 40 \ m\Omega \ MAX. \ (@ \ V_{GS} = 10 \ V, \ I_{D} = 15 \ A) \\ R_{DS(on)2} = 60 \ m\Omega \ MAX. \ (@ \ V_{GS} = 4 \ V, \ I_{D} = 15 \ A) \end{array}$

- Low Ciss Ciss = 1500 pF TYP.
- Built-in G-S Gate Protection Diodes
- High Avalanche Capability Ratings

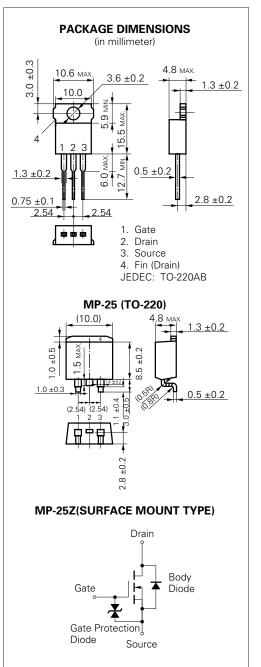
QUALITY GRADE

Standard

Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

ABSOLUTE MAXIMUM RATINGS (TA = 25 °C)

Drain to Source Voltage	Vdss	60	V		
Gate to Source Voltage	Vgss	±20	V		
Drain Current (DC)	D(DC)	±30	А		
Drain Current (pulse)*	D(pulse)	±120	А		
Total Power Dissipation (T _c = 25 $^{\circ}$ C)	P⊤1	75	W		
Total Power Dissipation (T _A = 25 $^{\circ}$ C)	Рт2	1.5	W		
Channel Temperature	Tch	150	°C		
Storage Temperature	Tstg	–55 to +150	°C		
Single Avalanche Current**	las	30	А		
Single Avalanche Energy**	Eas	90	mJ		
* PW \leq 10 μ s, Duty Cycle \leq 1 %					
** Starting T _{ch} = 25 °C, R _G = 25 Ω , V _{GS} = 20 V \rightarrow 0					



The information in this document is subject to change without notice.

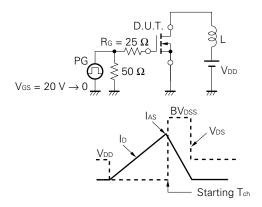
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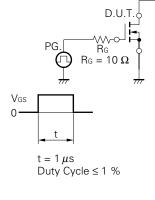
ELECTRICAL CHARACTERISTICS (TA = 25 °C)

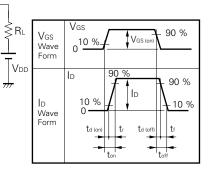
CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS
Drain to Source On-Resistance	RDS(on)1		31	40	mΩ	Vgs = 10 V, Id = 15 A
Drain to Source On-Resistance	RDS(on)2		40	60	mΩ	Vgs = 4 V, Id = 15 A
Gate to Source Cutoff Voltage	V _{GS(off)}	1.0	1.5	2.0	V	Vds = 10 V, Id = 1 mA
Forward Transfer Admittance	y _{fs}	15	27		S	$V_{DS} = 10 V, I_{D} = 15 A$
Drain Leakage Current	IDSS			10	μΑ	$V_{DS} = 60 V, V_{GS} = 0$
Gate to Source Leakage Current	lgss			±10	μΑ	$V_{GS} = \pm 20 \text{ V}, \text{ V}_{DS} = 0$
Input Capacitance	Ciss		1500		pF	$V_{DS} = 10 V$
Output Capacitance	Coss		720		pF	Vgs = 0
Reverse Transfer Capacitance	Crss		190		pF	f = 1 MHz
Turn-On Delay Time	td(on)		20		ns	I _D = 15 A
Rise Time	tr		260		ns	$V_{GS(on)} = 10 V$
Turn-Off Delay Time	td(off)		130		ns	$V_{DD} = 30 V$
Fall Time	tr		150		ns	$R_G = 10 \Omega$
Total Gate Charge	QG		50		nC	ID = 30 A
Gate to Source Charge	Q _{GS}		5.0		nC	V _{DD} = 48 V
Gate to Drain Charge	Qgd		15		nC	Vgs = 10 V
Body Diode Forward Voltage	V _{F(S-D)}		1.1		V	IF = 30 A, VGS = 0
Reverse Recovery Time	trr		110		ns	IF = 30 A, VGS = 0
Reverse Recovery Charge	Qrr		320		nC	di/dt = 100 A/µs

Test Circuit 1 Avalanche Capability

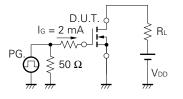
Test Circuit 2 Switching Time





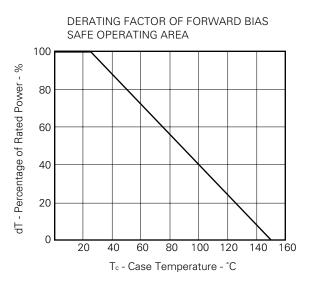


Test Circuit 3 Gate Charge

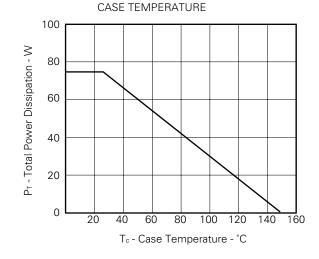


The application circuits and their parameters are for references only and are not intended for use in actual design-in's.

TOTAL POWER DISSIPATION vs.



TYPICAL CHARACTERISTICS (TA = 25 °C)

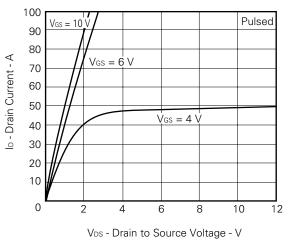


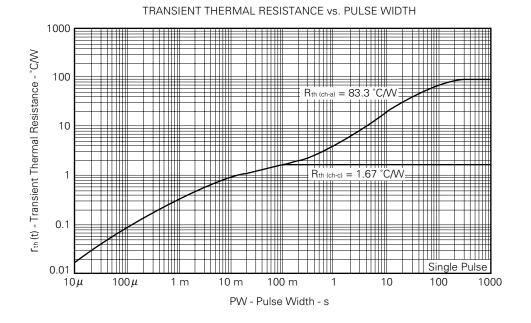
FORWARD BIAS SAFE OPERATING AREA 1000 Y ID - Drain Current - A D (pulse) 10 100 L O, 1 ١D (DC 10 Tc = 25 °C Single Pulse 1 0.1 1 10 100 VDS - Drain to Source Voltage - V

FORWARD TRANSFER CHARACTERISTICS Total and the second se

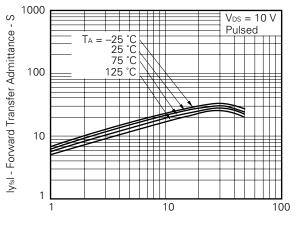
 V_{GS} - Gate to Source Voltage - V

DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



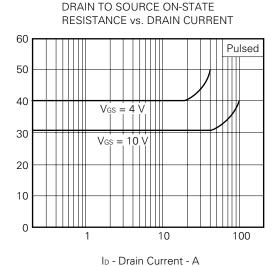


FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

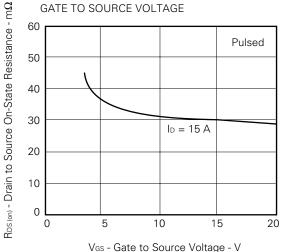


ID - Drain Current - A

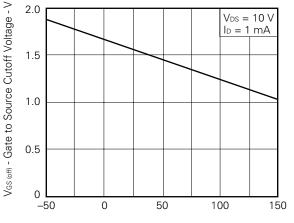
 $R_{DS\,(on)}$ - Drain to Source On-State Resistance - $m\Omega$



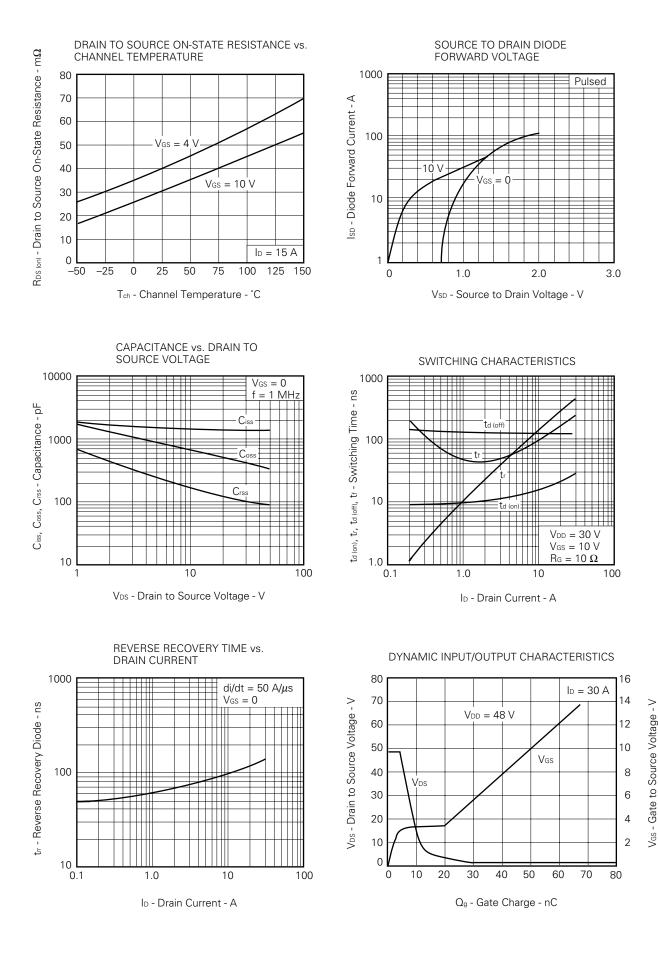
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

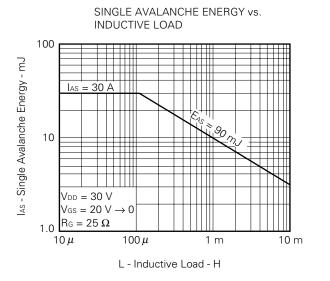


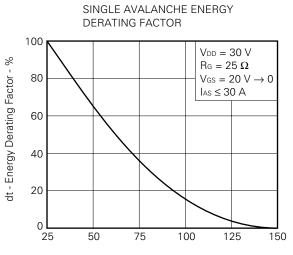
GATE TO SOURCE CUTOFF VOLTAGE vs. CHANNEL TEMPERATURE



Tch - Channel Temperature - °C







Starting T_{ch} - Starting Channel Temperature - °C

REFERENCE

Document Name	Document No.
NEC semiconductor device reliability/quality control system.	TEI-1202
Quality grade on NEC semiconductor devices.	IEI-1209
Semiconductor device mounting technology manual.	IEI-1207
Semiconductor device package manual.	IEI-1213
Guide to quality assurance for semiconductor devices.	MEI-1202
Semiconductor selection guide.	MF-1134
Power MOS FET features and application switching power supply.	TEA-1034
Application circuits using Power MOS FET.	TEA-1035
Safe operating area of Power MOS FET.	TEA-1037

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device is actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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Standard: Computer, Office equipment, Communication equipment, Test and Measurement equipment, Machine tools, Industrial robots, Audio and Visual equipment, Other consumer products, etc.

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